

<b>Notice of References Cited</b>	Application/Control No. 10/716,469		Applicant(s)/Patent Under Reexamination HSIEH ET AL.	
	Examiner Martin J. Angebranndt		Art Unit 1756	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,636,476	10-2003	Arakawa et al.	369/283
*	B	US-5,689,497	11-1997	Wilting et al.	369/275.1
*	C	US-2002/0001285	01-2002	Takeshima et al.	369/290
*	D	US-5,580,633	12-1996	Kuwahara et al.	428/825.1
*	E	US-RE35,947	11-1998	Kosinski et al.	428/64.1
*	F	US-4,735,889	04-1988	Namba et al.	430/270.16
*	G	US-2002/0054974	05-2002	Takahashi et al.	428/64.4
*	H	US-6,496,898	12-2002	Tsutsui, Kyoya	711/112
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	04-277558	10-1992	Japan	Kawashima et al.	***
	O	03-263624	01-1991	Japan	Nakao et al.	***
	P	63-308741	12-1988	Japan	Hiraoka et al.	***
	Q	10-124843	05-1998	Japan	Chiba	***
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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